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CONFIRMATION NO. 3715

SERIAL NUMBER	FILING OR 371(c) DATE	CLASS	GROUP ART UNIT	ATTORNEY DOCKET NO.
10/731,511	12/09/2003	438	2812	BUR920010031US2
<b>RULE</b>				
<b>APPLICANTS</b> Wagdi W. Abadeer, Jericho, VT; Erle Adler, Jericho, VT; Jeffrey S. Brown, Middlesex, VT; Robert J. Gauthier JR., Hinesburg, VT; Jonathan M. McKenna, Ann Arbor, MI; Jed H. Rankin, South Burlington, VT; Edward W. Sengle, Hinesburg, VT; William R. Tonti, Essex Junction, VT;				
<b>** CONTINUING DATA *****</b> <i>Yes</i> This application is a DIV of 10/449,426 05/30/2003 PAT 6,770,907 which is a DIV of 09/989,850 11/20/2001 PAT 6,624,031				
<b>** FOREIGN APPLICATIONS *****</b> <i>No</i>				
<b>IF REQUIRED, FOREIGN FILING LICENSE GRANTED</b> <b>** 03/10/2004</b>				
Foreign Priority claimed <input type="checkbox"/> yes <input checked="" type="checkbox"/> no 35 USC 119 (a-d) conditions met <input type="checkbox"/> yes <input checked="" type="checkbox"/> no <input type="checkbox"/> Met after Allowance Verified and Acknowledged <i>Andrew Stevenson</i> Examiner's Signature Initials		STATE OR COUNTRY VT	SHEETS DRAWING 22	TOTAL CLAIMS 19
		INDEPENDENT CLAIMS 5		
<b>ADDRESS</b> 24241				
<b>TITLE</b> Test structure and methodology for semiconductor stress-induced defects and antifuse based on same test structure				
<b>FILING FEE RECEIVED</b> 942	FEES: Authority has been given in Paper No. _____ to charge/credit DEPOSIT ACCOUNT No. _____ for following:		<input type="checkbox"/> All Fees <input type="checkbox"/> 1.16 Fees ( Filing ) <input type="checkbox"/> 1.17 Fees ( Processing Ext. of time ) <input type="checkbox"/> 1.18 Fees ( Issue ) <input type="checkbox"/> Other _____ <input type="checkbox"/> Credit	